



BSI Standards Publication

Semiconductor devices — Mechanical and climatic test methods

Part 41: Standard reliability testing methods of non-volatile memory devices

National foreword

This British Standard is the UK implementation of EN IEC 60749-41:2020. It is identical to IEC 60749-41:2020.

The UK participation in its preparation was entrusted to Technical Committee EPL/47, Semiconductors.

A list of organizations represented on this committee can be obtained on request to its committee manager.

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